FUNCTIONAL DIAGRAM

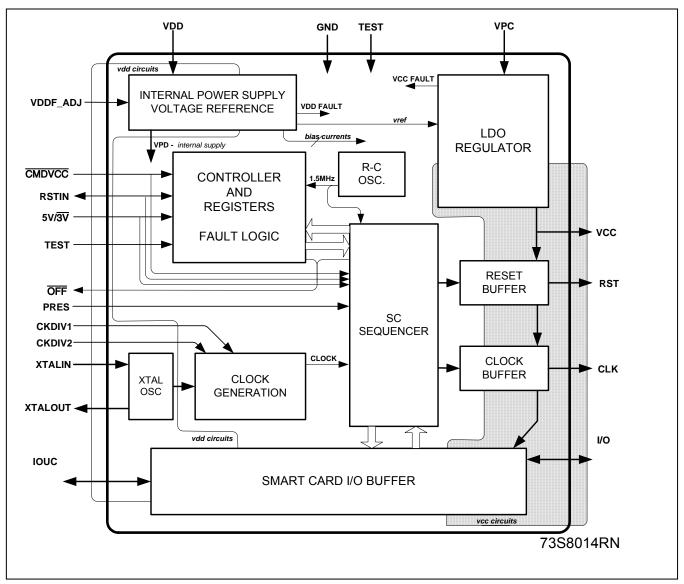


Figure 1: 73S8014RN Block Diagram

Table of Contents

1	Pin	10ut	5
2	Ele	ectrical Specifications	
	2.1	Absolute Maximum Ratings	
	2.2	Recommended Operating Conditions	8
	2.3	Package Thermal Parameters	
	2.4	Smart Card Interface Requirements	
	2.5	Characteristics: Digital Signals	
	2.6	DC Characteristics	12
	2.7	Voltage Fault Detection Circuits	12
3	Ap	plications Information	
	3.1	Example 73S8014RN Schematics	
	3.2	NDS Precautions	
	3.3	System Controller Interface	
	3.4	Power Supply and Voltage Supervision	
	3.5	Card Power Supply	
	3.6	On-Chip Oscillator and Card Clock	
	3.7	Activation Sequence	
	3.8	Deactivation Sequence	
	3.9	Fault Detection and OFF	
	3.10	I/O Circuitry and Timing	
4	•	uivalent Circuits	
5	Me	chanical Drawing	
6	Orc	dering Information	
7	Rel	lated Documentation	27
8		ntact Information	
R		on History	
		······································	

Figures

Figure 17: Oscillator Circuit	Figure 1: 73S8014RN Block Diagram Figure 2: 73S8014RN 20-SOP Pin Out Figure 3: 73S8014RN – Typical Application Schematic Figure 4: Activation Sequence – RSTIN Low When \overline{CMDVCC} Goes Low Figure 5: Activation Sequence – RSTIN High When \overline{CMDVCC} Goes Low Figure 6: Deactivation Sequence Figure 7: Timing Diagram – Management of the Interrupt Line \overline{OFF} . Figure 8: I/O and I/OUC State Diagram Figure 9: I/O – I/OUC Delays – Timing Diagram Figure 10: Open Drain type – \overline{OFF} Figure 11: Power Input/Output Circuit, V _{DD} , V _{PC} , V _{CC} Figure 12: Type 5 – Smart Card CLK Driver Circuit Figure 13: Type 6 – Smart Card RST Driver Circuit Figure 14: Type 7A – Smart Card IO Interface Circuit Figure 15: Type 7B – Smart Card IOUC Interface Circuit Figure 16: Type 8 – General Input Circuit Figure 17: Oscillator Circuit Figure 18: VDD _{FLT_ADJ}	14 16 17 18 19 20 20 21 21 22 22 23
Figure 18: VDD _{FLT_ADJ}	Figure 18: VDD _{FLT_ADJ} Figure 19: Mechanical Drawing 20-Pin SO Package	25 26

Tables

6
8
8
8
9
11
12
12
27

1 Pinout

The 73S8014RN is supplied as 20-pin SO package.

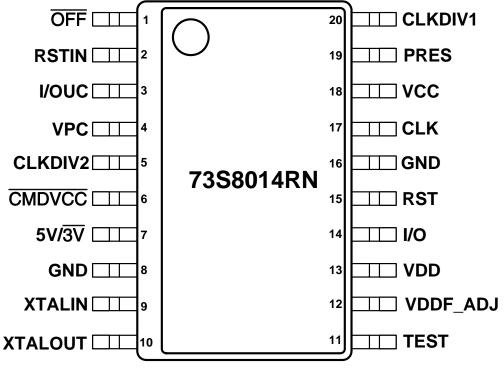


Figure 2: 73S8014RN 20-SOP Pin Out

Table 1 provides the 73S8014RN pin names, pin numbers, type, equivalent circuits and descriptions.

Pin Name	Pin Number	Туре	Equivalent Circuit	Description			
Card Interface							
I/O	14	ю	Figure 14	Card I/O: Data signal to/from card. Includes an 11K pull-up resistor to V_{CC}			
RST	15	0	Figure 13	Card reset: provides reset (RST) signal to card.			
CLK	17	0	Figure 12	Card clock: provides clock signal (CLK) to card. The rate of this clock is determined by the external crystal frequency or frequency of the external clock signal applied on XTALIN and CLKDIV selections.			
PRES	19	Ι	Figure 16	Card Presence switch: active high indicates card is present. Includes a high-impedance pull-down current source.			
VCC	18	PSO	Figure 11	Card power supply – logically controlled by sequencer, output of LDO regulator. Requires an external filter capacitor to the card GND.			
GND	16	GND	-	Card ground.			
Host Processor	Interface						
CMDVCC	6	I	Figure 16	Command VCC (negative assertion): Logic low on this pin causes the LDO regulator to ramp the V_{CC} supply to the card and initiates a card activation sequence, if a card is present.			
5V/ 3V	7	I	Figure 16	5 volt / 3 volt card selection: Logic high selects 5 volts for V_{CC} and card interface, logic low selects 3 volt operation. When the part is to be used with a single card voltage, this pin should be tied to either GND or V_{DD} . However, it includes a high impedance pull-up resistor to default this pin high (selection of 5V card) when not connected. This pin shall not be changed when CMDVCC is low.			
CLKDIV1 CLKDIV2	20 5	I	Figure 16	Sets the divide ratio from the XTAL oscillator (or external clockinput) to the card clock. These pins include a pull-up resistor forCLKDIV1 and CLKLDIV2 to provide a default rate of divide bytwo.CLKDIV1CLKDIV2000101110XTALIN/4100XTALIN/2			
OFF	1	0	Figure 10	Interrupt signal to the processor. Active Low - Multi-function indicating fault conditions and card presence. Open drain output configuration – It includes an internal $20k\Omega$ pull-up to V _{DD} .			
RSTIN	2	Ι	Figure 16	Reset Input: This signal is the reset command to the card.			
I/OUC	3	10	Figure 15	System controller data I/O to/from the card. Includes an 11K pull-up resistor to V_{DD}			

Table 1: 73S8014RN 20-Pin SOP Pin Definitions

Miscellaneous Inputs and Outputs							
XTALIN	9		Figure 17	Crystal oscillator input: can either be connected to crystal or driven as a source for the card clock.			
XTALOUT	XTALOUT 10 F			Crystal oscillator output: connected to crystal. Left open if XTALIN is being used as external clock input.			
VDDF_ADJ 12			Figure 18	V_{DD} fault threshold adjustment input: this pin can be used to adjust the V_{DDF} value (that controls deactivation of the card). Must be left open if unused.			
Power Supply a	nd Ground	t					
VDD	VDD 13 PSO Figure 11 System interface supply voltage and supply voltage for internal circuitry.						
VPC 4 PSO Figure 11 LDO regulator power		LDO regulator power supply source.					
TEST	TEST 11 – Test pin. Should be tied to GND.			Test pin. Should be tied to GND.			
GND 8 GND – Digital ground.							

2 Electrical Specifications

This section provides the following:

- Absolute maximum ratings
- Recommended operating conditions
- Package thermal parameters
- Smart card interface requirements
- Digital signals characteristics
- DC Characteristics
- Voltage Fault Detection Circuits

2.1 Absolute Maximum Ratings

Table 2 lists the maximum operating conditions for the 73S8014RN. Permanent device damage may occur if absolute maximum ratings are exceeded. Exposure to the extremes of the absolute maximum rating for extended periods may affect device reliability. The smart card interface pins are protected against short circuits to V_{CC} , ground, and each other.

Parameter	Rating
Supply Voltage V _{DD}	-0.5 to 6.0 VDC
Supply Voltage V _{PC}	-0.5 to 6.0 VDC
Input Voltage for Digital Inputs	-0.3 to (V _{DD} +0.5) VDC
Storage Temperature	-60 to 150°C
Pin Voltage (except card interface)	-0.3 to (V _{DD} +0.5) VDC
Pin Voltage (card interface)	-0.3 to (V _{CC} + 0.5) VDC
ESD Tolerance – Card interface pins	+/- 6kV
ESD Tolerance – Other pins	+/- 2kV

Table 2: Absolute Maximum Device Ratings

* Note: ESD testing on smart card pins is HBM condition, 3 pulses, each polarity referenced to ground. Note: Smart Card pins are protected against shorts between any combinations of Smart Card pins.

2.2 Recommended Operating Conditions

Function operation should be restricted to the recommended operating conditions specified in Table 3.

Parameter	Rating
Supply Voltage V _{DD}	2.7 to 5.5 VDC
Supply Voltage V _{PC}	4.75 to 5.5 VDC
Ambient Operating Temperature	-40°C to +85°C
Input Voltage for Digital Inputs	0V to V _{DD} + 0.3V

2.3 Package Thermal Parameters

Error! Reference source not found. lists the 73S8014RN Smart Card package thermal parameters.

Table 4: Package Thermal Parameters

Parameter	Rating
20 SO	50°C / W

2.4 Smart Card Interface Requirements

Table 5 lists the 73S8014RN Smart Card interface requirements.

Symbol	Parameter	Condition	Min	Nom	Max	Unit
General c	er Supply (V _{cc}) Regu onditions, -40℃ < T < litions, 4.85V < V _{PC} < 5	85 °C, 4.75V < V_{PC} < 5.5V, 2.7V < V_{DD} < 5	5.5V			
		Inactive mode	-0.1		0.1	V
		Inactive mode, I _{CC} = 1mA	-0.1		0.4	V
		Active mode; I _{CC} <65mA; 5V	4.65		5.25	V
		Active mode; I _{CC} <65mA; 5V, NDS condition	4.75		5.25	V
		Active mode; I _{CC} <65mA; 3V	2.85		3.15	V
	Card supply voltage including ripple and noise	Active mode; single pulse of 100mA for 2μs; 5V, fixed load = 25mA	4.6		5.25	V
V_{CC}		Active mode; single pulse of 100mA for 2μ s; 3V, fixed load = 25mA	2.76		3.2	V
		Active mode; current pulses of 40nAs with peak I _{CC} <200mA, t <400ns; 5V	4.6		5.25	v
		Active mode; current pulses of 40nAs with peak I _{CC} <200mA, t <400ns; 5V, NDS condition	4.65		5.25	V
		Active mode; current pulses of 40nAs with peak I _{CC} <200mA, t <400ns; 3V	2.76		3.15	v
V _{CCrip}	V _{cc} Ripple	f _{RIPPLE} = 20K – 200MHz			350	mV
I _{CCmax}	Card supply output	Static load current, V _{CC} >4.6 or 2.7 volts as selected	65			mA
oomax	current	Static load current, V _{CC} >1.62 ⁽¹⁾	40			mA
I _{CCF}	I _{CC} fault current		70		130	mA
V _{SR}	V _{CC} slew rate, rise	$C_F = 1.0 \mu F$ on V_{CC}	0.06	0.150	0.30	V/μs
V _{SF}	V _{CC} slew rate, fall	$C_F = 1.0 \mu F$ on V_{CC}	0.075	0.150	0.60	V/μs
C _{FNDS}	External filter cap (V _{CC} to GND)	NDS applications, C_F should be ceramic with low ESR (<100m Ω).	0.5	1.0	1.5	μF

Symbol	Parameter	Condition	Min	Nom	Max	Unit
Interface	Requirements – Data Signals: I	/O and Host Interface	s: I/OUC.			
I_{SHORTL}, I_{SHORTL}	_{IORTH} , and V _{INACT} requirements o	to not pertain to I/OUC	2.			
	Output level, high (I/OUC)	I _{ОН} =0	$0.9 V_{\text{DD}}$		V _{DD} +0.1	V
		I _{OH} = -40μA	$0.75 V_{\text{DD}}$		V _{DD} +0.1	V
V _{OH}		I _{ОН} =0	$0.9 V_{CC}$		V _{CC} +0.1	V
	Output level, high (I/O)	I _{OH} = -40μA (V _{CC} = 3/5V)	0.75 V _{CC}		V _{CC} +0.1	V
	Output level, low (I/OUC)	I _{OL} =1mA			0.3	V
V _{OL}		Vcc = 5V			0.45	V
	Output level, low (I/O)	Vcc = 3V			0.2	V
	Input level, high (I/OUC)		0.6 V _{DD}		V _{DD} +0.30	V
V _{IH}	Input level, high (I/O)		0.6 V _{CC}		V _{CC} +0.30	V
. /	Input level, low		-0.3		0.8	V
VIL	Input level, low (I/O)	Vcc = 5V, 3V	-0.3		0.8	V
	Output voltage when outside	I _{OL} = 0			0.1	V
VINACT	of session	I _{OL} = 1mA			0.3	V
I _{LEAK}	Input leakage	$V_{IH} = V_{CC}$			10	μA
I _{IL}	Input current, low	V _{IL} = 0			0.65	mA
I _{SHORTL}	Short circuit output current	For output low, shorted to V_{CC} through 33 Ω			15	mA
I _{SHORTH}	Short circuit output current	For output high, shorted to ground through 33 Ω			15	mA
t _R , t _F	Output rise time, fall times	C _L = 80pF, 10% to 90%.			100	ns
t _{IR} , t _{IF}	Input rise, fall times				1	μS
R _{PU}	Internal pull-up resistor	Output stable for >400ns	8	11	14	kΩ
FD _{MAX}	Maximum data rate				1	MHz
T _{FDIO}	Delay, I/O to I/OUC, I/OUC to I/O, (respectively falling edge	Edge from master to slave, measured at	60	100	200	ns
T _{RDIO}	to falling edge and rising edge to rising edge)	50%		15		ns
C _{IN}	Input capacitance				10	pF

Symbol	Parameter	Condition	Min	Nom	Max	Unit
Reset and	Clock for Card Interface, R	ST, CLK				•
V _{OH}	Output level, high	I _{OH} =-200μA	0.9 V _{CC}		V _{cc}	V
M		I _{OL} =200μA, V _{CC} = 5V	0		0.45	V
V _{OL}	Output level, low	I _{OL} =200μA, V _{CC} = 3V	0		0.2	V
V	Output voltage when	I _{OL} = 0			0.1	V
VINACT	outside of session	I _{OL} = 1mA			0.3	V
I _{RST_LIM}	Output current limit, RST				30	mA
I _{CLK_LIM}	Output current limit, CLK				70	mA
CLK _{SR3V}	CLK slew rate	<	0.3			V/ns
CLK _{SR5V}	CLK slew rate	Vcc = 5V	0.5			V/ns
		C _L = 35pF for CLK, 10% to 90%			8	ns
t _R , t _F	Output rise time, fall time	C _L = 200pF for RST, 10% to 90%			100	ns
δ	Duty cycle for CLK	$\begin{array}{l} C_{\text{L}} \text{ =35pF}, \\ F_{\text{CLK}} \leq 20 \text{MHz} \\ C_{\text{L}} \text{ =35pF} \end{array}$	45		55	%

2.5 Characteristics: Digital Signals

Table 6 lists the 73S8014RN digital signals characteristics.

Table 6: Digital Signals Characteristics

Symbol	Parameter	Condition	Min	Nom	Max	Unit
Digital I/O	Except for XTALIN and XTALO	UT				
V _{IL}	Input Low Voltage		-0.3		0.8	V
V _{IH}	Input High Voltage		1.8		V _{DD} + 0.3	V
V _{OL}	Output Low Voltage	I _{OL} = 2mA			0.45	V
V _{OH}	Output High Voltage	I _{ОН} = -1mA	V _{DD} - 0.45			V
R _{OUT}	Pull-up resistor, OFF		16	20	24	kΩ
I _{IL1}	Input Leakage Current	$GND < V_{IN} < V_{DD}$	-5		5	μA
I _{IL2}	Input Leakage Current	GND < V _{IN} < V _{DD} CLKDIV2 only	-15		15	μA

Oscillato	Oscillator (XTALIN) I/O Parameters						
VILXTAL	Input Low Voltage - XTALIN		-0.3		$0.3 V_{\text{DD}}$	V	
VIHXTAL	Input High Voltage - XTALIN		$0.7 V_{DD}$		V _{DD} +0.3	V	
I _{ILXTAL}	Input Current - XTALIN	$GND < V_{IN} < V_{DD}$	-30		30	μA	
f _{MAX}	Max freq. Osc or external clock				27	MHz	
δin	External input duty cycle limit	tR/F < 10% fIN, 45% < δ _{CLK} < 55%	48		52	%	

2.6 DC Characteristics

Table 7 lists the 73S8014RN DC characteristics.

Symbol	Parameter	Condition	Min	Nom	Max	Unit
		12 MHz XTAL		2.7	7.0	mA
		Ext CLK, V _{DD} = 2.7 – 3.6V, V _{CC} Off		1.7		mA
I _{DD}	Supply Current	Ext CLK, V _{DD} = 2.7 – 3.6V, V _{CC} On		2.2		mA
		Ext CLK, V _{DD} = 4.5 – 5.5V, V _{CC} Off		2.7		mA
		Ext CLK, V _{DD} = 4.5 – 5.5V, V _{CC} On				mA
I _{PC}	Supply Current	V _{CC} on, ICC=0 I/O, AUX1, AUX2=high, Clock not toggling		450	700	μΑ
I _{PCOFF}	V_{PC} supply current when $V_{CC} = 0$	CMDVCC High		345	650	μA

Table 7: DC Characteristics

2.7 Voltage Fault Detection Circuits

Table 8 lists the 73S8014RN Voltage Fault Detection Circuits.

Table 8: Voltage Fault Detection Circuits

Symbol	Parameter	Condition	Min	Nom	Max	Unit
V _{DDF}	V_{DD} fault (V_{DD} Voltage supervisor threshold)	No external resistor on VDDF_ADJ pin	2.15		2.4	V
V	V _{cc} fault	$V_{CC} = 5v$			4.6	V
V_{CCF}	(V _{CC} Voltage supervisor threshold)	V _{CC} = 3v			2.7	V

3 Applications Information

This section provides general usage information for the design and implementation of the 73S8014RN. The documents listed in Related Documentation provide more detailed information.

3.1 Example 73S8014RN Schematics

Figure 3 shows a typical application schematic for the implementation of the 73S8014RN.

Note that minor changes may occur to the reference material from time to time and the reader is encouraged to contact Teridian for the latest information.

3.2 NDS Precautions

Preliminary testing against the NDS specification has found that the coupled noise level on the I/O signal may approach the maximum NDS limits. Teridian recommends adding capacitor footprints on the CLK, RST and I/O signals for addition of small capacitors to filter system noise if needed. These footprints should be added at or near the smart card connector interface. A typical value of 27pF has been found to reduce the noise to acceptable levels where the noise is an issue. In addition, Teridian recommends the addition of a 0 ohm series resistor in the CLK path. If the CLK output is found to generate too much system noise, a small resistor can be substituted to create a small RC network to slow the CLK edges and reduce the CLK noise to the rest of the system. The amount of the noise being generated from the CLK signal depends on many factors including; board layout and component placement, clock input source, distance between 8014 and the card interface, etc. Lastly, some isolation between the CLK signal should be provided against all other system signals, especially the RST and I/O signals.

73S8014RN Data Sheet

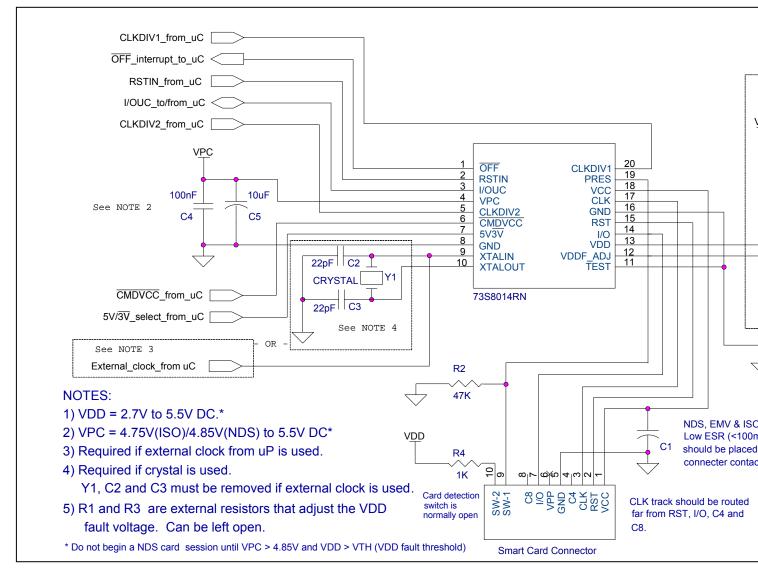


Figure 3: 73S8014RN – Typical Application Schematic

3.3 System Controller Interface

Three digital inputs allow direct control of the card interface by the host. The 73S8014RN is controlled as follows:

- Pin CMDVCC: When asserted low, starts an activation sequence
- Pin RSTIN: controls the card RST signal (when enabled by the sequencer)
- Pin $5V/\overline{3V}$: Defines the card V_{DD} voltage (5V when high and 3V when low)

Interrupt output to the host: As long as the card is not activated, the \overline{OFF} pin informs the host about the card presence only (Low = No card in the reader). When \overline{CMDVCC} is asserted low (Card activation sequence requested from the host), low level on \overline{OFF} means a fault has been detected (e.g. card removal during card session, voltage fault, or over-current fault) that automatically initiates a deactivation sequence.

3.4 Power Supply and Voltage Supervision

The Teridian 73S8014RN smart card interface ICs incorporate a LDO voltage regulator for V_{CC}. The voltage output is controlled by the digital input $5V/\overline{3V}$ of the 73S8014RN. This regulator is able to provide either 3V or 5V card voltage from the power supply applied on the V_{PC} pin. The voltage regulator can provide a current of at least 65mA on V_{CC} for both 3V and 5V that complies with EMV 4.0 and NDS specifications.

Digital circuitry is powered by the power supply applied on the VDD pin. V_{DD} also defines the voltage range to interface with the system controller. A card deactivation sequence is forced upon fault of any of this voltage supervisor. One voltage supervisor constantly monitors the V_{DD} voltage. It is used to initialize the ISO-7816-3 sequencer at power-on, and to deactivate the card at power-off or upon fault. The voltage threshold of the V_{DD} voltage supervisor is internally set by default to 2.26V nominal. However, it may be desirable, in some applications, to modify this threshold value.

The method of adjusting the V_{DD} fault voltage is to use a resistive network of R3 from the VDDF_ADJ pin to V_{DD} supply and R1 from the VDDF_ADJ pin to ground (see application schematics). In order to set the new threshold voltage, the equivalent voltage divider ratio must be determined. This ratio value will be designated Kx. Kx is defined as R1/(R1+R3). Kx is calculated as:

Kx = $(2.71 / V_{TH})$ - 0.595 where V_{TH} is the desired new threshold voltage.

To determine the values of R1 and R3, use the following formulas (the parallel resistance of R1 and R3 is selected to be 24000 ohms)

R3 = 24000 / Kx $R1 = R3^{*}(Kx / (1 - Kx))$

Taking the example above, where a V_{DD} fault threshold voltage of 2.6V is desired, solving for Kx gives: \rightarrow Kx = (2.71 / 2.6) - 0.595 = 0.4473.

Solving for R3 gives: \rightarrow R3 = 24000 / 0.4473 = 53654. Solving for R1 gives: \rightarrow R1 = 58752 *(0.4473 / (1 – 0.4473)) = 43422. Using standard 1 % resistor values gives R3 = 53.6K Ω and R1 = 43.2K Ω .

Using 1% external resistors and a parallel resistance of 24K ohms will result in a +/- 6% tolerance in the value of VDD Fault. The sources of variation due to integrated circuit process variations and mismatches include the internal reference voltage (less than +/- 1%), the internal comparator hysteresis and offset (less than +/- 1.7% for part-to-part, processing and environment), the internal resistor value mismatch and value variations (less than 1.8%), and the external resistor values (1%).

If the 2.26V default threshold is used, this pin must be left unconnected.

Note: Since the V_{DD} and the V_{PC} power supplies are separate, special care must be taken to insure that the V_{PC} voltage is greater than 4.85V before beginning a card session. In addition, VDD must be greater than the threshold for VDD fault before card activation. Card activation begins on the falling edge of \overline{CMDVCC} and therefore it must be at VDD when the VDD and VPC supplies power up. When turning off power to the V_{DD} and the V_{PC} power supplies, the card session should be terminated before shutdown or the V_{PC} power supply must remain higher than 4.85V when the VDD fault is detected and the emergency deactivation sequence is completed.

3.5 Card Power Supply

The card power supply is internally provided by the LDO regulator, and controlled by the digital ISO-7816-3 sequencer.

3.6 On-Chip Oscillator and Card Clock

The 73S8014RN devices have an on-chip oscillator that can generate the smart card clock using an external crystal (connected between the pins XTALIN and XTALOUT) to set the oscillator frequency. When the clock signal is available from another source, it can be connected to the pin XTALIN, and the pin XTALOUT should be left unconnected. The 73S8014RN is capable of generating the 4.5, 6.75 and 13.5MHz NDS clock frequencies using a crystal or external source set at 27MHz.

The card clock frequency may be chosen between 4 different division rates, defined by digital inputs CLKDIV 1 and CLKDIV 2, as per the following table:

CLKDIV1	CLKDIV2	CLK	Max XTALIN
0	0	1/6 XTALIN	27MHz
0	1	1⁄4 XTALIN	27MHz
1	0	XTALIN	20MHz
1	1	1∕₂ XTALIN	27MHz

3.7 Activation Sequence

The 73S8014RN smart card interface ICs have an internal 10ms delay on the application of V_{DD} where V_{DD} > V_{DDF} . No activation is allowed during this 10ms period. The CMDVCC (edge triggered) signal must then be set low to activate the card. In order to initiate activation, the card must be present; there can be no V_{DD} fault.

The following steps show the activation sequence and the timing of the card control signals when the system controller sets CMDVCC low while the RSTIN is low:

- CMDVCC is set low at t₀.
- V_{CC} will rise to the selected level and then the internal V_{CC} control circuit checks the presence of V_{CC} at the end of t_1 . In normal operation, the voltage V_{CC} to the card becomes valid before t_1 . If V_{CC} is not valid at t_1 , the OFF goes low to report a fault to the system controller, and V_{CC} to the card is shut off.
- Turn I/O to reception mode at t_2 .
- CLK is applied to the card at t_3 .
- RST is a copy of RSTIN after t₃.

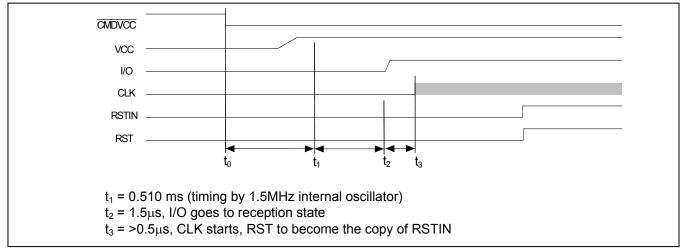
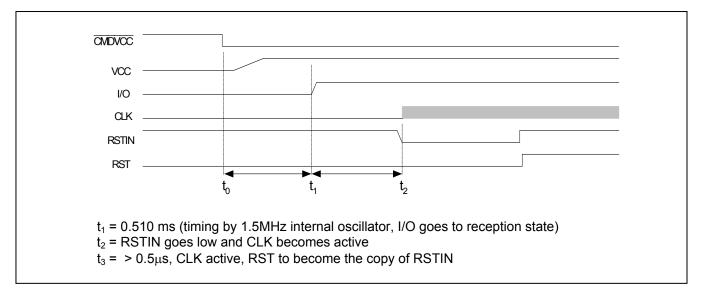


Figure 4: Activation Sequence – RSTIN Low When CMDVCC Goes Low

The following steps show the activation sequence and the timing of the card control signals when the system controller pulls the CMDVCC low while the RSTIN is high:

- CMDVCC is set low at t₀.
- V_{CC} will rise to the selected level and then the internal V_{CC} control circuit checks the presence of V_{CC} at the end of t_1 . In normal operation, the voltage V_{CC} to the card becomes valid before t_1 . If V_{CC} is not valid at t_1 , the OFF goes low to report a fault to the system controller, and V_{CC} to the card is shut off.
- At the fall of RSTIN at t₂, CLK is applied to the card
- RST is a copy of RSTIN after t₂.





3.8 Deactivation Sequence

Deactivation is initiated either by the system controller by setting the CMDVCC high, or automatically in the event of hardware faults. Hardware faults are over-current, V_{DD} fault, V_{CC} fault, and card extraction during the session.

The following steps show the deactivation sequence and the timing of the card control signals when the system controller sets the CMDVCC high or OFF goes low due to a fault or card removal:

- RST goes low at the end of t₁.
- CLK is set low at the end of t₂.
- I/O goes low at the end of t_3 . Out of reception mode.
- V_{CC} is shut down at the end of time t₄. After a delay t₅ (discharge of the V_{CC} capacitor), V_{CC} is low.

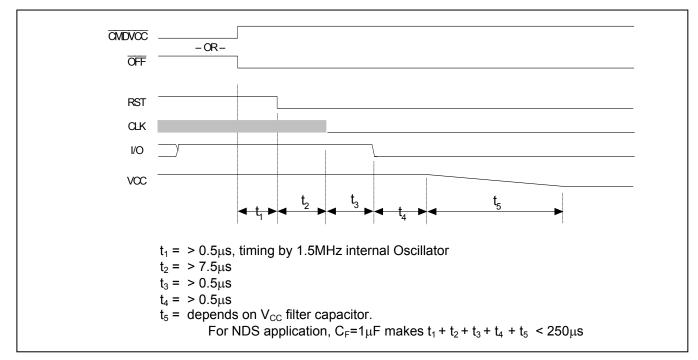


Figure 6: Deactivation Sequence

3.9 Fault Detection and OFF

There are two different cases that the system controller can monitor the OFF signal: to query regarding the card presence outside card sessions, or for fault detection during card sessions.

Outside a card session: In this condition, <u>CMDVCC</u> is always high, <u>OFF</u> is low if the card is not present, and high if the card is present. Because it is outside a card session, any fault detection will not act upon the <u>OFF</u> signal. No deactivation is required during this time.

During a card session: CMDVCC is always low, and OFF falls low if the card is extracted or if any fault detection is detected. At the same time that OFF is set low, the sequencer starts the deactivation process.

Figure 7 shows the timing diagram for the signals CMDVCC, PRES, and OFF during a card session and outside the card session:

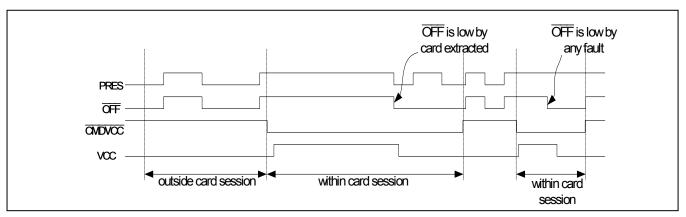


Figure 7: Timing Diagram – Management of the Interrupt Line OFF

3.10 I/O Circuitry and Timing

The state of the I/O pin is low after power on reset and it goes high when the activation sequencer turns on the I/O reception state. See the Activation Sequence section for details on when the I/O reception is enabled. The state of I/OUC is high after power on reset.

Within a card session and when the I/O reception state is turned on, the first I/O line on which a falling edge is detected becomes the input I/O line and the other becomes the output I/O line. When the input I/O line rising edge is detected then both I/O lines return to their neutral state.

Note: In certain situations and conditions, the I/O logic can get confused if the host and the card attempt to drive the IOUC and the I/O signal low at the same time. It should be noted that this is an illegal condition as all card communication is initiated by the host with a command/response protocol. The next host command should not be sent until a valid response has been completely received from the card. However, if this condition should occur, the 8014 may set both the IOUC and the I/O as outputs where they are both driven low at the same time. When either side drives their respective signal high, then this mode should be released. However, if there is a series resistance between the host and the 8014, then there may not be enough drive to release this mode. If the series resistance is greater than about 100 ohms, then this may cause this mode to become locked for the duration of the card session. If the host detects this condition (IOUC held low for more than one byte time), the card session must be terminated and restarted.

Figure 8 shows the state diagram of how the I/O and I/OUC lines are managed to become input or output. The delay between the I/O signals is shown in Figure 9.

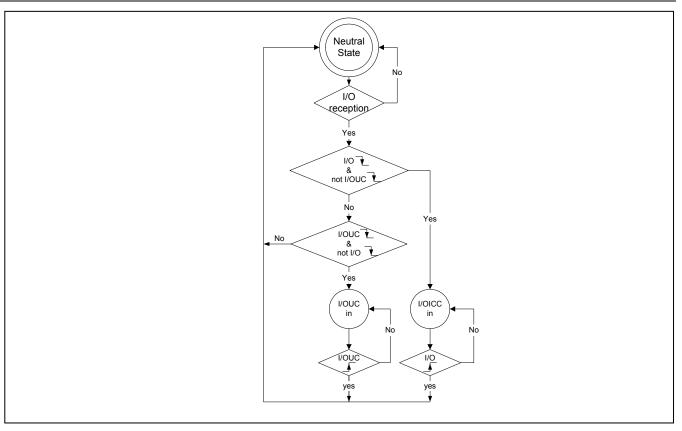


Figure 8: I/O and I/OUC State Diagram

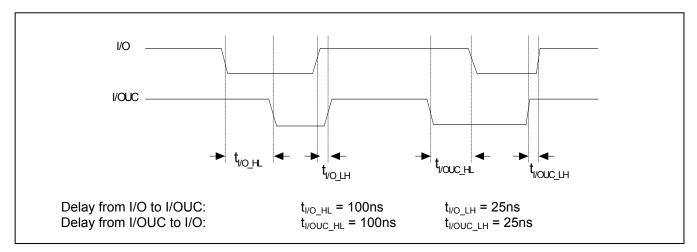


Figure 9: I/O – I/OUC Delays – Timing Diagram

4 Equivalent Circuits

This section provides illustrations of circuits equivalent to those described in the pinout section.

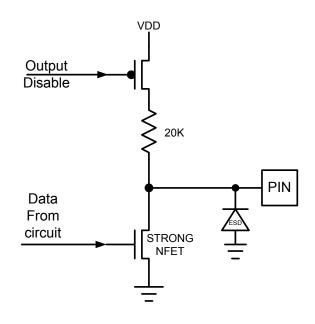


Figure 10: Open Drain type – OFF

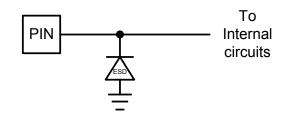


Figure 11: Power Input/Output Circuit, V_{DD}, V_{PC}, V_{CC}

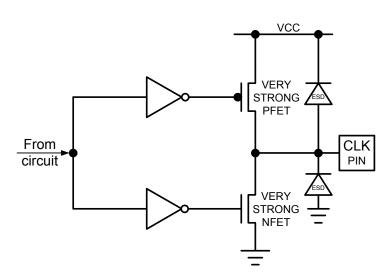


Figure 12: Type 5 – Smart Card CLK Driver Circuit

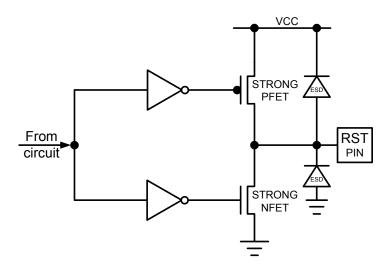


Figure 13: Type 6 – Smart Card RST Driver Circuit

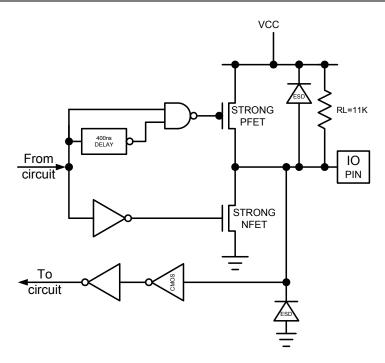


Figure 14: Type 7A – Smart Card IO Interface Circuit

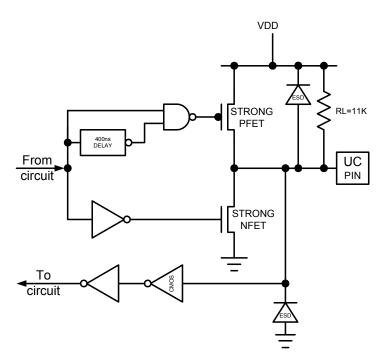
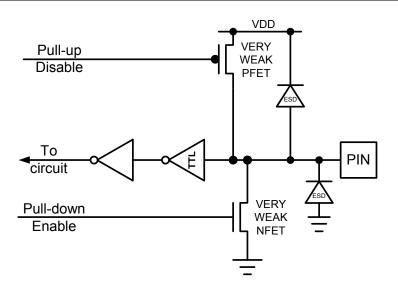


Figure 15: Type 7B – Smart Card IOUC Interface Circuit



Note: Pins CMDVCC, 5V/3V, CLKDIV1 and CLKDIV2 have the pull-up enabled. Pins RSTIN, CLKIN, PRES have the pull-down enabled.

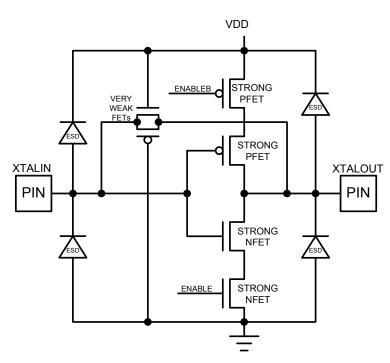
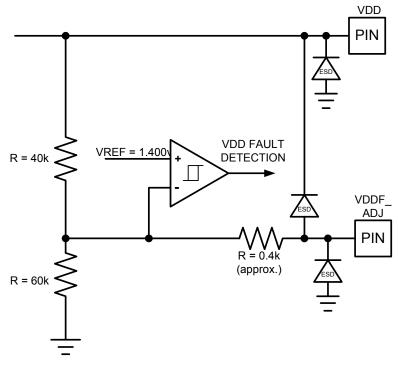
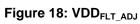




Figure 17: Oscillator Circuit





5 Mechanical Drawing

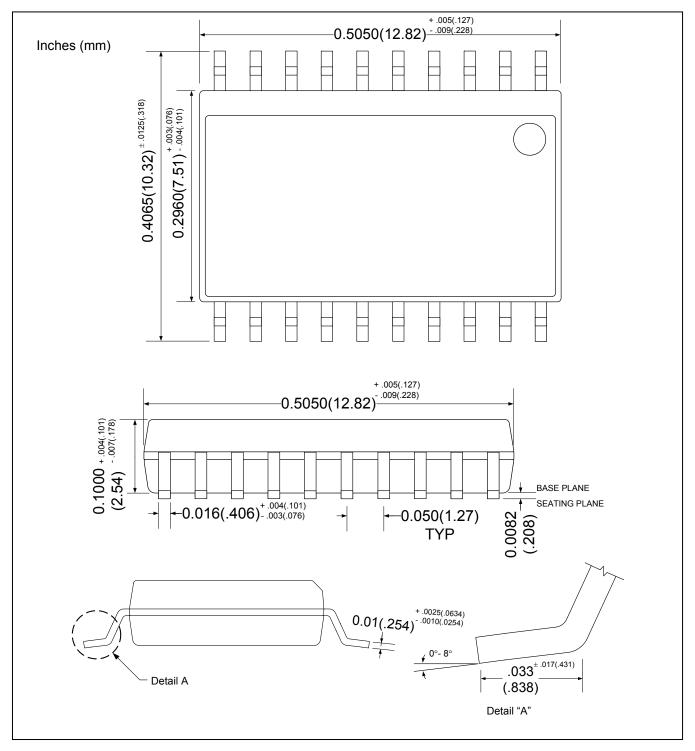


Figure 19: Mechanical Drawing 20-Pin SO Package

6 Ordering Information

Table 9 lists the order numbers and packaging marks used to identify 73S8014RN products.

Part Description	Order Number	Packaging Mark
73S8014RN 20-pin Lead-Free	73S8014RN-IL/F	73S8014RN
73S8014RN 20-pin Lead-Free Tape / Reel	73S8014RN-ILR/F	73S8014RN

Table 9: Order Numbers and Packaging Marks

7 Related Documentation

The following 73S8014RN document is available from Teridian Semiconductor Corporation:

73S8014R/RN/RT 20SO Demo Board User Manual

8 Contact Information

For more information about Teridian Semiconductor products or to check the availability of the 73S8014RN, contact us at:

6440 Oak Canyon Road Irvine, CA 92618-5201

Telephone: (714) 508-8800 FAX: (714) 508-8878 Email: scr.support@teridian.com

For a complete list of worldwide sales offices, go to http://www.teridian.com.

Revision History

Revision	Date	Description
1.0	12/22/2008	First publication.

© 2008 Teridian Semiconductor Corporation. All rights reserved. Teridian Semiconductor Corporation is a registered trademark of Teridian Semiconductor Corporation. Simplifying System Integration is a trademark of Teridian Semiconductor Corporation. All other trademarks are the property of their respective owners.

Teridian Semiconductor Corporation makes no warranty for the use of its products, other than expressly contained in the Company's warranty detailed in the Teridian Semiconductor Corporation standard Terms and Conditions. The company assumes no responsibility for any errors which may appear in this document, reserves the right to change devices or specifications detailed herein at any time without notice and does not make any commitment to update the information contained herein. Accordingly, the reader is cautioned to verify that this document is current by comparing it to the latest version on http://www.teridian.com or by checking with your sales representative.

Teridian Semiconductor Corp., 6440 Oak Canyon Rd., Suite 100, Irvine, CA 92618 TEL (714) 508-8800, FAX (714) 508-8877, http://www.Teridian.com

Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

Maxim Integrated:

73S8014RN-IL/F 73S8014RN-ILR/F 73S8014RN-IL/F1 73S8014RN-ILR/F1